

# Thorsten Mehrrens

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/1998789/publications.pdf>

Version: 2024-02-01

10  
papers

193  
citations

1307594

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1372567

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11  
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docs citations

11  
times ranked

368  
citing authors

#	ARTICLE	IF	CITATIONS
1	Theoretical study of precision and accuracy of strain analysis by nano-beam electron diffraction. Ultramicroscopy, 2015, 158, 38-48.	1.9	43
2	Nanosopic Insights into InGaN/GaN Core-Shell Nanorods: Structure, Composition, and Luminescence. Nano Letters, 2016, 16, 5340-5346.	9.1	43
3	Optimization of the preparation of GaN-based specimens with low-energy ion milling for (S)TEM. Micron, 2012, 43, 902-909.	2.2	24
4	Conventional Transmission Electron Microscopy Imaging beyond the Diffraction and Information Limits. Physical Review Letters, 2014, 113, 096101.	7.8	21
5	Quantitative HAADF STEM of SiGe in presence of amorphous surface layers from FIB preparation. Ultramicroscopy, 2018, 184, 29-36.	1.9	17
6	Strain analysis from nano-beam electron diffraction: Influence of specimen tilt and beam convergence. Ultramicroscopy, 2018, 190, 45-57.	1.9	17
7	Measurement of local crystal lattice strain variations in dealloyed nanoporous gold. Materials Research Letters, 2018, 6, 84-92.	8.7	10
8	Quantitative Strain and Compositional Studies of In <sub>x</sub> Ga <sub>1-x</sub> As Epilayer in a GaAs-based pHEMT Device Structure by TEM Techniques. Microscopy and Microanalysis, 2014, 20, 1262-1270.	0.4	7
9	GaN tubes with coaxial non-polar and semipolar GaInN quantum wells. Physica Status Solidi C: Current Topics in Solid State Physics, 2014, 11, 648-651.	0.8	6
10	Accuracy and precision of position determination in ISTEM imaging of BaTiO <sub>3</sub> . Ultramicroscopy, 2021, 227, 113325.	1.9	2